DW PACKAGE (TOP VIEW)
$GND \begin{bmatrix} 1 \\ 24 \end{bmatrix} 1 \overline{OE}$
1Y1 2 23 1Y3 1Y2 3 22 1A
GND [] 4 21 [] V <sub>CC</sub> 2Q1 [] 5 20 [] PRE
$2\overline{OE}$ [ 6 19 ] 2Q3
2A [] 7 18 [] GND
GND 9 16 V <u>CC</u> 3Y1 10 15 3OE
3Y2 11 14 3Y3
GND [12 13] 3A

• Packaged in Plastic Small-Outline Package

### description

The CDC330 is a high-performance, low-skew clock driver. It is specifically designed for applications requiring output signals at both the primary clock frequency and one-half the primary clock frequency.

This device contains two banks that fan out one input to three same-frequency outputs and one bank that fans out one input to four half-frequency outputs with minimum skew for clock distribution. Each bank of Y outputs switch in phase and at the same frequency as its clock (A) input. The four Q outputs switch at one-half the frequency of their clock  $(2\overline{A})$  input.

When the output-enable ( $2\overline{OE}$ ) input is low and the preset ( $\overline{PRE}$ ) input is high, the Q outputs toggle on high-to-low transitions of  $2\overline{A}$ . Taking  $\overline{PRE}$  low asynchronously presets the Q outputs to the high level. When a bank's  $\overline{OE}$  input is high, the outputs are in the high-impedance state.

The CDC330 is characterized for operation from 0°C to 70°C.

nY1–nY3
Z
L
Н

FUNCTION TABLE	ES
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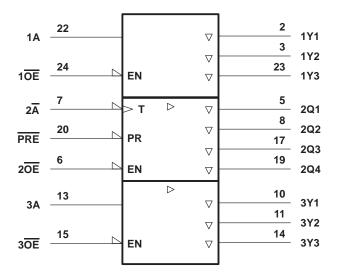
	INPUTS	OUTPUTS	
2 <mark>0E</mark>	PRE	2Ā	2Q1–2Q3
Н	Х	Х	Z
L	L	L	н
L	Н	$\downarrow$	Toggle

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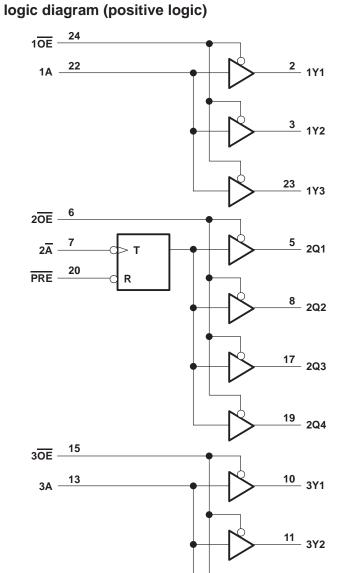
## CDC330 CLOCK DRIVER WITH 3-STATE OUTPUTS

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## logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



<u>14</u> 3Y3



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$ Input voltage range, $V_I$ (see Note 1) Voltage range applied to any output in the disabled or power-off state, $V_O$ – Current into any output in the low state, $I_O$ Input clamp current, $I_{IK}$ ( $V_I < 0$ ) Output clamp current, $I_{OK}$ ( $V_O < 0$ ) Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)	-0.5 V to 7 V 0.5 V to 5.5 V 96 mA 18 mA 50 mA
Maximum power dissipation at T <sub>A</sub> = 55°C (in still air) (see Note 2) Storage temperature range, T <sub>stg</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the Package Thermal Considerations application note in the 1994 ABT Advanced BiCMOS Technology Data Book, literature number SCBD002B.

### recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
VCC	Supply voltage	4.75	5.25	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
IOH	High-level output current		-32	mA
I <sub>OL</sub>	Low-level output current		32	mA
TA	Operating free-air temperature	0	70	°C

NOTE 3: Unused pins (input or I/O) must be held high or low.

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
VIK	V <sub>CC</sub> = 4.75 V,	l <sub>l</sub> = –18 mA				-1.2	V
VOH	V <sub>CC</sub> = 4.75 V,	I <sub>OH</sub> = - 32 mA		2			V
VOL	V <sub>CC</sub> = 4.75 V,	I <sub>OL</sub> = 32 mA				0.5	V
IIН	V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 2.7 V				50	μA
١ <sub>١L</sub>	V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 0.5 V				-50	μA
I <sub>OZ</sub>	V <sub>CC</sub> = 5.25 V,	$V_{O} = V_{CC} \text{ or } GND$				±50	μΑ
۱ <sub>0</sub> §	V <sub>CC</sub> = 5.25 V,	$V_{O} = 2.5 V$		-30		-180	mA
			Outputs high		11	40	
ICC	$V_{CC} = 5.25 V,$ $V_{I} = V_{CC} \text{ or GND}$	$I_{O} = 0,$	Outputs low		15	30	mA
			Outputs disabled		10	30	
Ci	VI = 2.5 V or 0.5 V				3		pF
Co	$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$				9		pF

<sup>‡</sup> All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25^{\circ}C$ .

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.



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### timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			MIN	MAX	UNIT
fclock	Clock frequency	1A/3A (duty cycle 40 – 60%)		67	MHz
		$2\overline{A}$ (duty cycle 40 – 60%)		100	MHz
t <sub>w</sub>		1A/3A low	5.9		
		1A/3A high	5.9		
	Pulse duration	2A low	2.8		ns
		2A high	4.5		
		PRE low	3		
t <sub>su</sub>	Setup time	PRE inactive before $2\overline{A}\downarrow$	2		ns

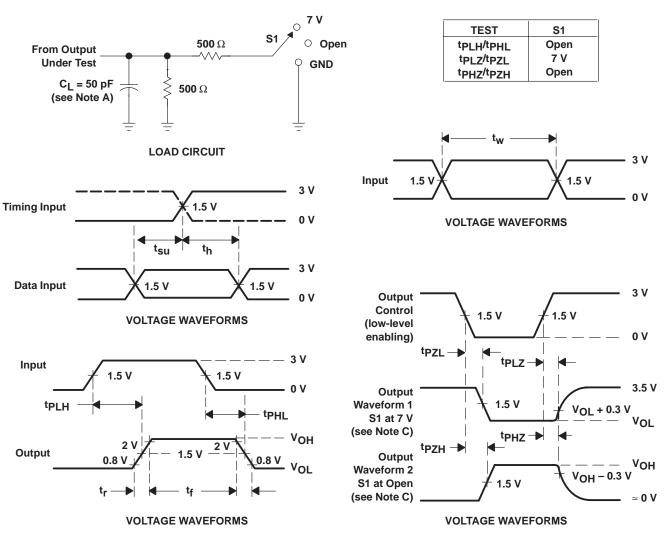
# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 4 and Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN MAX	UNIT
<i>,</i> +	1A or 3A	Any 1Y or 3Y	67	MHz
f <sub>max</sub> †	2 <mark>Ā</mark>	Any Q	100	IVIHZ
<sup>t</sup> PLH	· · <del>·</del>		11	
<sup>t</sup> PHL	Any A or $\overline{A}$	Any Y or Q	10.5	ns
<sup>t</sup> PHL	PRE	Any Q	12.5	ns
<sup>t</sup> PZH		Any Y or Q	9	
<sup>t</sup> PZL	Any OE		8.5	ns
<sup>t</sup> PHZ		Any Y or Q	8.5	ns
<sup>t</sup> PLZ	Any OE	Ally For Q	9	115
	1A	Any 1Y	0.4	
	3A	Any 3Y	0.4	
<sup>t</sup> sk(o)	1A or 3A	Any 1Y or 3Y	0.5	ns
	2A	Any Q	0.4	
<sup>t</sup> sk(pr)	Any A or A	Any Y or Q	1	ns

<sup>†</sup> Duty cycle 40 - 60%

NOTE 4: All specifications are valid only for all outputs switching.





### PARAMETER MEASUREMENT INFORMATION

#### NOTES: A. CL includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. D. The outputs are measured one at a time with one transition per measurement.

### Figure 1. Load Circuit and Voltage Waveforms



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nA nY1 tPLH1 TPHL1 nY2 tPLH2 tPHL2 tPLH9 PHL9 nY3 ► tPLH3 ItPLH10 🕨 tPHL3 🖊 tPHL10 2Ā 2Q1 <sup>t</sup>PLH4 🕨 tPHL4 🛤 2Q2 tPLH5 tPHL5 2Q3 ► <sup>t</sup>PHL6 tPLH6 🛃 2Q4 ▶ t<sub>PLH7</sub> 😽 🔺 tPHL7 🖛

### PARAMETER MEASUREMENT INFORMATION

NOTES: A. Output skew,  $t_{Sk(0)}$ , is calculated as the greater of:

- The difference between the fastest and slowest of  $t_{PLHn}$  (n = 1, 2, 3) The difference between the fastest and slowest of  $t_{PLHn}$  (n = 4, 5, 6, 7)
- The difference between the fastest and slowest of  $t_{PLHn}$  (n = 8, 9, 10)
- The difference between the fastest and slowest of  $t_{PHLn}$  (n = 1, 2, 3)
- The difference between the fastest and slowest of  $t_{PHLn}$  (n = 4, 5, 6, 7)
- The difference between the fastest and slowest of tpHLn (n = 8, 9, 10)
- B. Process skew, tsk(pr), is calculated the same as output skew, tsk(o), across multiple CDC330 devices under identical operating conditions.

## Figure 2. Waveforms for Calculation of t<sub>sk(o)</sub>, t<sub>sk(pr)</sub>



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